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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/698,169	10/31/2003	Sheldon Aronowitz	02-6037/LS11P218	9839	
75	90 01/03/2005		EXAMINER		
LSI Logic Corporation			MAI, ANH D		
1551 McCarthy Boulevard Milpitas, CA 95035			ART UNIT	PAPER NUMBER	
1 ,			2814		
			DATE MAILED: 01/03/2009	DATE MAILED: 01/03/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Av -
	Application No.	Applicant(s)
Office Action Commons	10/698,169	ARONOWITZ ET AL.
Office Action Summary	Examiner	Art Unit
7	Anh D. Mai	2814
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the (correspondence address
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a reply be tingly within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	nely filed rs will be considered timely. In the mailing date of this communication. ID (35 U.S.C. § 133).
Status		
 1) ⊠ Responsive to communication(s) filed on 14 E 2a) ☐ This action is FINAL. 2b) ☒ This 3) ☐ Since this application is in condition for allowa 	s action is non-final.	osecution as to the ments is
closed in accordance with the practice under t	Ex parte Quayle, 1935 C.D. 11, 4	53 _, O.G. 213.
Disposition of Claims		•
4) ⊠ Claim(s) 1-20 is/are pending in the application 4a) Of the above claim(s) 3,7-9 and 12-20 is/a 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) 1,2,4-6,10 and 11 is/are rejected. 7) □ Claim(s) is/are objected to. 8) □ Claim(s) are subject to restriction and/or	re withdrawn from consideration.	
Application Papers		
9)☐ The specification is objected to by the Examine 10)☒ The drawing(s) filed on 31 October 2003 is/are Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)☐ The oath or declaration is objected to by the E	e: a)⊠ accepted or b)⊡ objected or b)□ object	e 37 CFR 1.85(a). ojected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documen 2. Certified copies of the priority documen 3. Copies of the certified copies of the priority documen application from the International Burea * See the attached detailed Office action for a list	ts have been received. ts have been received in Applicat prity documents have been receiv nu (PCT Rule 17.2(a)).	ion No ed in this National Stage
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date 10/31/2003.	4) Interview Summar Paper No(s)/Mail D 5) Notice of Informal 6) Other:	

DETAILED ACTION

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Election/Restrictions

Applicant's election without traverse of species B, claims 1, 2, 4-6, 10 and 11 in the reply 1. filed on December 14, 2004 is acknowledged.

Drawings

2. The drawings are objected to under 37 CFR 1.83(a). The drawings must show every feature of the invention specified in the claims. Therefore, the "semiconductor integrated circuit having the semiconductor memory devices formed thereon" (as recited in claim 10) must be shown or the feature(s) canceled from the claim(s). No new matter should be entered.

Corrected drawing sheets in compliance with 37 CFR 1.121(d) are required in reply to the Office action to avoid abandonment of the application. Any amended replacement drawing sheet should include all of the figures appearing on the immediate prior version of the sheet, even if only one figure is being amended. The figure or figure number of an amended drawing should not be labeled as "amended." If a drawing figure is to be canceled, the appropriate figure must be removed from the replacement sheet, and where necessary, the remaining figures must be renumbered and appropriate changes made to the brief description of the several views of the drawings for consistency. Additional replacement sheets may be necessary to show the renumbering of the remaining figures. The replacement sheet(s) should be labeled "Replacement Sheet" in the page header (as per 37 CFR 1.84(c)) so as not to obstruct any portion of the drawing figures. If the changes are not accepted by the examiner, the applicant will be notified

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and informed of any required corrective action in the next Office action. The objection to the drawings will not be held in abeyance.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1, 2, 4-6, 10 and 11 are rejected under 35 U.S.C. 102(b) as being anticipated by Wu et al. (U.S. Patent No. 6,445,030).

With respect to claim 1, Wu teaches a semiconductor memory device as claimed including:

a semiconductor substrate (52);

a dielectric gate stack (56) formed on a channel region of the substrate (52), the dielectric gate stack (56) having a top portion and a bottom portion;

the dielectric gate stack (56) including an electron trapping layer (56b) of electron trapping material; and

a gate electrode (58) connected with the top portion of the gate stack (56). (See Fig. 7).

With respect to claim 2, the electron trapping material (56b) of Wu includes hafnium oxide.

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With respect to claim 4, the dielectric gate stack (56) of Wu includes a first layer (56a) of dielectric material and a second layer (56c) of dielectric material configured such that the first layer (56a) of dielectric material is formed on the channel region of the substrate (52) and the electron trapping layer (56b) is formed on the first layer (56a) of dielectric material and wherein the second layer (56c) of dielectric material is formed on the electron trapping layer (56b).

With respect to claim 5, the first layer (56a) of dielectric material and the second layer (56c) of dielectric material of Wu are each comprised of silicon oxide.

With respect to claim 6, the first layer (56a) of dielectric material of Wu can be formed of a different dielectric material than the second layer (56c) of dielectric material.

With respect to claim 10, the semiconductor integrated circuit of Wu having the semiconductor memory devices formed thereon.

With respect to claim 11, Wu teaches a semiconductor memory device as claimed including:

a semiconductor substrate (52) having a source and a drain (60/62) separated by a channel region;

a first dielectric layer (56a) formed on the channel region of the substrate (52); an electron trapping layer (56b) formed on the first dielectric layer (56a); a second dielectric layer (56c) formed on the electron trapping layer (56b); and a gate electrode (58) connected with the second dielectric layer (56c). (See Fig. 7).

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Conclusion

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Anh D. Mai whose telephone number is (571) 272-1710. The examiner can normally be reached on 9:00AM-5:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Anh D. Mai //

December 22/, 2004